Notice of References Cited	Application/Control No. 10/679,446	Applicant(s)/Patent Under Reexamination TAKIZAWA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,715,351	02-1973	Brooker et al.	548/156
*	B	US-2,860,984	11-1958	JONES JEAN E	430/572
*	C	US-2,435,865	02-1948	ANISH ALFRED W	548/156
*	D	US-4,876,356	10-1989	Dust et al.	548/419
*	E	US-3,864,337	02-1975	Owen, John R.	548/156
*	F	US-4,551,413	11-1985	Bell, Vivien L.	430/270.2
*	G	US-6,187,502	02-2001	Chapman et al.	430/201
*	H	US-5,459,025	10-1995	Hioki, Takanori	430/570
*	I	US-4,080,496	03-1978	Mee, John David	544/295
*	J	US-5,891,738	04-1999	Soini et al.	436/501
*	K	US-5,079,128	01-1992	Katagiri et al.	430/269
*	L	US-2004/0204513	10-2004	Takizawa et al.	522/002
*	M	US-2004/0245432	12-2004	Takizawa, Hiroo	250/208.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	02-004582	01-1990	Japan	Yabe et al.	***
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Feldner et al., "Non-linear optical properties of specific polymethines: influence of substitutents and chain length", MCLC S&T Sec. B, Nonlinear Optics vol. 26(1-3) pp. 99-106 (2000)(abstract only)
	V	Foucault et al., "Two photon absorption in organic dyes relation with the symmetry of levels", Optics Comm. Vol. 15(3) pp. 412-415 (1975)(abstract only)
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/679,446	Applicant(s)/Patent Under Reexamination TAKIZAWA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0019711	01-2005	Takizawa, Hiroo	430/561
*	B	US-2004/0131969	07-2004	Takizawa et al.	430/270.18
*	C	US-2,955,939	10-1960	WHITE FRANK L; et. al.	430/578
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.